TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

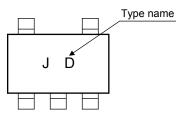
# TC7SZ38F,TC7SZ38FU

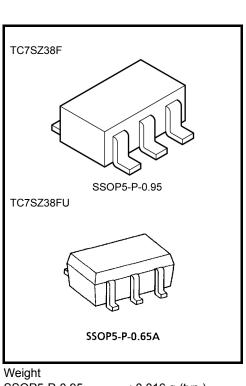
2-Input NAND Gate(Open Drain Output)

#### Features

- High output drive: 24 mA (min) @VCC = 3 V
- Super high speed operation:
  - $t_{pz} = 2.2 \text{ ns}(typ.)@V_{CC} = 5 \text{ V}, 50 \text{ pF}$
- Operation voltage range: V<sub>CC</sub> (opr) =  $1.80 \sim 5.5$  V
- 5.5V tolerant inputs.
- Power down protection is provided on output.
- Matches the performance of TC74LCX series when operated at 3.3 V  $V_{\rm CC}.$

#### Marking

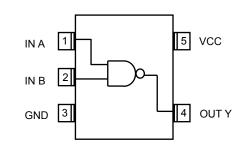




SSOP5-P-0.95 SSOP5-P-0.65A

: 0.016 g	(typ.)
: 0.006 g	(typ.)

#### Pin Assignment (top view)



Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit	
Power supply voltage	V <sub>CC</sub>	-0.5~6	V	
DC input voltage	V <sub>IN</sub>	-0.5~6	V	
DC output voltage	V <sub>OUT</sub>	-0.5~6	V	
Input diode current	lık	-20	mA	
Output diode current	I <sub>OK</sub>	-20	mA	
DC output current	IOUT	50	mA	
DC V <sub>CC</sub> /ground current	Icc	±50	mA	
Power dissipation	PD	200	mW	
Storage temperature	T <sub>stg</sub>	-65~150	°C	
Lead temperature (10s)	ΤL	260	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

# Logic Diagram



## Truth Table

Input		Output
А	В	Y
L	L	*Z
L	Н	*Z
Н	L	*Z
Н	Н	L

\*: High Impedance

### **Operating Ranges**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	1.8~5.5	V
		1.5~5.5 (Note 1)	v
Input voltage	V <sub>IN</sub>	0~5.5	V
Output voltage	V <sub>OUT</sub>	0~5.5 (Note 2)	V
		0~V <sub>CC</sub> (Note 3)	v
Operating temperature	T <sub>opr</sub>	-40~85	°C
	dt/dv	0~20 (V_{CC} = 1.8 V, 2.5 V $\pm$ 0.2 V)	
Input rise and fall time		0~10 (V_{CC} = 3.3 V $\pm$ 0.3 V)	ns/V
		0~5 (V <sub>CC</sub> = 5.5 V $\pm$ 0.5 V)	

Note 1: Data retention only

Note 2: OFF state

Note 3: Low state

### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics		Cumbal	nbol Test Condition			Ta = 25°C			Ta = -40~85°C		Unit
Characteri			V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit		
	High level	VIH			1.8	$\begin{array}{c} 0.75 \times \\ V_{CC} \end{array}$	_	_	$\begin{array}{c} 0.75 \times \\ V_{CC} \end{array}$	_	· V
Input voltage	i ligit level	VН				$0.7 \times V_{CC}$		_	$0.7 \times V_{CC}$	_	
input voltage	Low level				1.8	_		$\begin{array}{c} 0.25 \times \\ V_{CC} \end{array}$	_	$\begin{array}{c} 0.25 \times \\ V_{CC} \end{array}$	
Low level	Lowiever	VIL				_		$0.3 \times V_{CC}$	—	$0.3 \times V_{CC}$	
High level output leakage current		I <sub>LKG</sub>	$V_{IN} = V_{IL}$		1.8~5.5	—		±5	—	±10	μΑ
			V <sub>IN</sub> = V <sub>IL</sub>	I <sub>OL</sub> = 100 μA	1.8		0	0.1		0.1	
Output voltage Low level		V <sub>OL</sub>			2.3		0	0.1		0.1	
					3.0	_	0	0.1	_	0.1	
					4.5		0	0.1		0.1	
	LOWIEVEI			I <sub>OL</sub> = 8 mA	2.3		0.1	0.3		0.3	
				l <sub>OL</sub> = 16 mA	3.0		0.15	0.4		0.4	
				I <sub>OL</sub> = 24 mA	3.0		0.22	0.55		0.55	
				I <sub>OL</sub> = 32 mA	4.5		0.22	0.55		0.55	
Input leakage curre	ut leakage current $I_{IN}$ $V_{IN} = 5.5$ V or GND		0~5.5			±1		±10	μA		
Power off leakage	current	I <sub>OFF</sub>	$V_{IN}$ or $V_{OUT} = 5.5 V$		0.0			1		10	μA
Quiescent supply of	current	Icc	$V_{IN} = V_{CC}$ or GND		5.5		_	2	—	20	μA

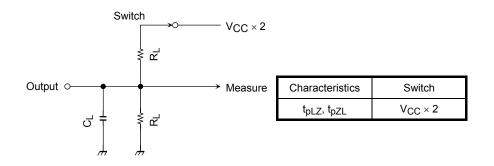
#### AC Characteristics (unless otherwise specified, Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta =4	Unit	
Characteristics	Symbol		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit
		$\begin{array}{l} C_L = 50 \ p F, \\ R_L = 500 \ \Omega \end{array}$	1.65	1.5	6.5	12.7	1.5	13.2	
			1.8	1.5	5.4	10.5	1.5	11.0	ns
	t <sub>pZL</sub>		$2.5\pm0.2$	0.8	3.5	7.0	0.8	7.5	
			$\textbf{3.3}\pm\textbf{0.3}$	0.8	2.8	5.0	0.8	5.2	
Propagation delay time			$5.0\pm0.5$	0.5	2.2	4.3	0.5	4.5	
	t <sub>pLZ</sub>	$\begin{array}{l} C_L = 50 \ p\text{F}, \\ R_L = 500 \ \Omega \end{array}$	1.65	1.5	5.5	12.7	1.5	13.2	ns
			1.8	1.5	4.6	10.5	1.5	11.0	
			$2.5\pm0.2$	0.8	3.0	7.0	0.8	7.5	
			$\textbf{3.3}\pm\textbf{0.3}$	0.8	2.1	5.0	0.8	5.2	
			$5.0 \pm 0.5$	0.5	1.3	4.3	0.5	4.5	
Input capacitance	C <sub>IN</sub>	—	0~5.5	_	4	_	_	_	pF
Output capacitance	C <sub>OUT</sub>		5.5		3			_	pF
Power dissipation capacitance	C <sub>PD</sub>	(Note 4)	3.3		6.7	_			pF
			5.5	_	13	_	_	_	μr

Note 4: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 

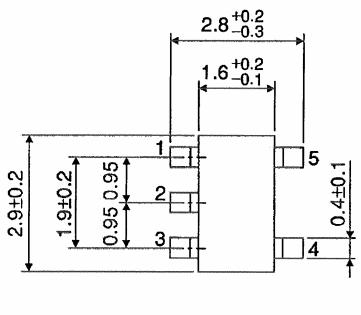
#### **AC Characteristics Measurement Circuit**

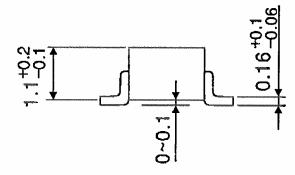


# Package Dimensions

SSOP5-P-0.95

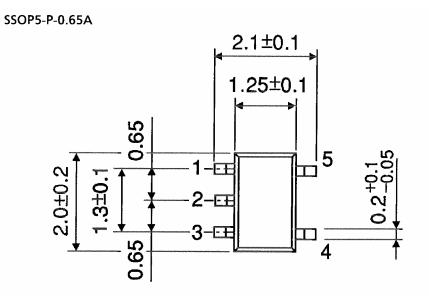
Unit : mm





Weight: 0.016 g (typ.)

# Package Dimensions



0.9±0.1

Weight: 0.006 g (typ.)

Unit : mm

#### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
  In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.).These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patents or other rights of TOSHIBA or the third parties.
- Please contact your sales representative for product-by-product details in this document regarding RoHS compatibility. Please use these products in this document in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses occurring as a result of noncompliance with applicable laws and regulations.